

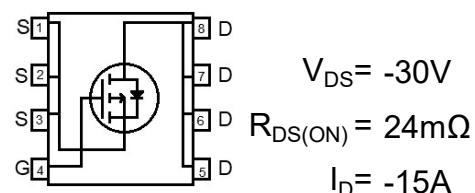


• General Description

It combines trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$.

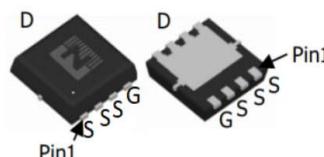
• Features

- Low $R_{DS(ON)}$ to minimize conductive loss
- High GOX reliability
- Low Thermal resistance



• Application

- BLDC Motor driver
- DC-DC
- Load switch



DFN3*3



HF

• Ordering Information:

Part NO.	ZM240P03M			
Marking	240P03			
Packing Information	REEL TAPE			
Basic ordering unit (pcs)	5000			

• Absolute Maximum Ratings ($T_C=25^\circ C$)

Parameter	Symbol	Conditions	Value	Unit
Drain-Source Voltage	V_{DS}		-30	V
Gate-Source Voltage	V_{GS}		± 20	V
Continuous Drain Current	I_D	$T_C=25^\circ C$	-15	A
	I_D	$T_C=75^\circ C$	-13	A
	I_D	$T_C=100^\circ C$	-10	A
Pulsed Drain Current	I_{DM}	Pulsed; $t_p \leq 10 \mu s$; $T_{mb} = 25^\circ C$	-60	A
Total Power Dissipation	P_D	$T_C=25^\circ C$	18	W
Total Power Dissipation	P_D	$T_A=25^\circ C$	0.9	W
Operating Junction Temperature	T_J		-55 to +150	°C
Storage Temperature	T_{STG}		-55 to +150	°C
Single Pulse Avalanche Energy	E_{AS}	$L=0.1mH$, $V_{GS}=-10V$, $R_g=25\Omega$,	45	mJ
		$L=0.5mH$, $V_{GS}=-10V$, $R_g=25\Omega$,	95	mJ
ESD Level (HBM)			CLASS 2	



•Thermal resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R _{thJC}		-	7.1	°C/W
Thermal resistance, junction-ambient ⁽¹⁾	R _{thJA}		-	140	°C/W
Soldering temperature (total time<10s)	T _{sold}		-	260	°C

•Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =-250uA	-30			V
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} =V _{DS} , I _D =-250uA	-1.2	-1.7	-2.5	V
Drain-Source Leakage Current	I _{DSS}	V _{GS} =0V, V _{DS} = -30V			1.0	uA
Gate- Source Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} = 0V			100	nA
Static Drain-source On Resistance	R _{DS(ON)}	V _{GS} =-10V, I _D = -12A		24	32	mΩ
		V _{GS} =-4.5V, I _D = -8A		37	55	mΩ
Forward Transconductance	g _{FS}	V _{DS} =-5V, I _{SD} = -5A		18		s
Diode Forward Voltage	V _{FSD}	V _{GS} =0V, I _{SD} = -12A			1.3	V

•Dynamic characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input capacitance	C _{iss}	f = 1MHz, V _{DS} =-25V	-	960	-	pF
Output capacitance	C _{oss}		-	106	-	
Reverse transfer capacitance	C _{rss}		-	63	-	
Gate Resistance	R _g	f = 1MHz	-	1.9		Ω
Total gate charge	Q _g	V _{DD} = -15V, I _D = -12A, V _{GS} = -10V	-	12	-	nC
	Q _g (4.5v)		-	6.5	-	
Gate - Source charge	Q _{gs}	V _{GS} = -10V	-	2.4	-	nC
Gate - Drain charge	Q _{gd}		-	2.8	-	
Turn-ON Delay time	t _{D(on)}	V _{GS} =-10V, V _{DS} =-15V, R _G =3.3Ω, I _D =-20A	-	10	-	ns
Turn-ON Rise time	t _r		-	15	-	ns
Turn-Off Delay time	t _{D(off)}		-	12	-	ns
Turn-Off Fall time	t _f		-	8	-	ns
Reverse Recovery Time	t _{RR}	V _{DD} =-20V, dI _S /dt = 100A/us, I _S =-20A	-	30	-	ns
Reverse Recovery Charge	Q _{RR}		-	12	-	nC



Fig.1 Gate-Charge Characteristics

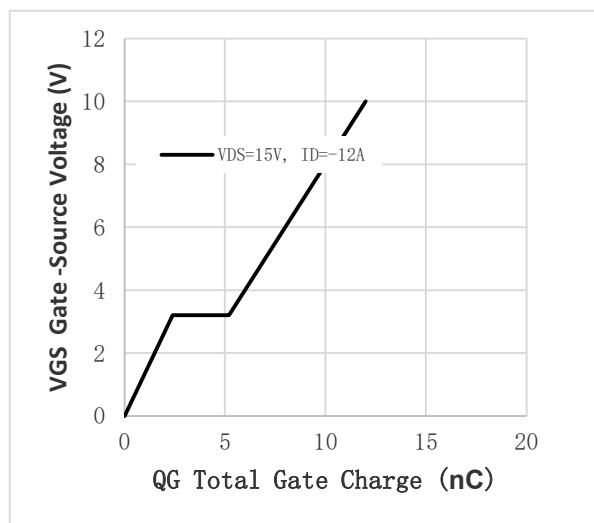


Fig.2 Capacitance Characteristics

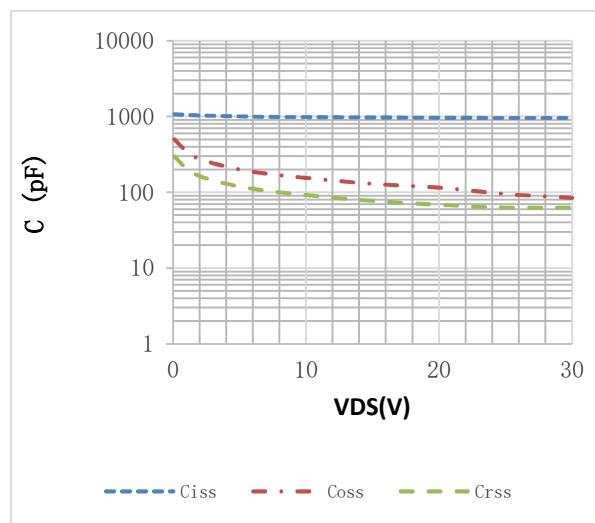


Fig.3 Power Dissipation

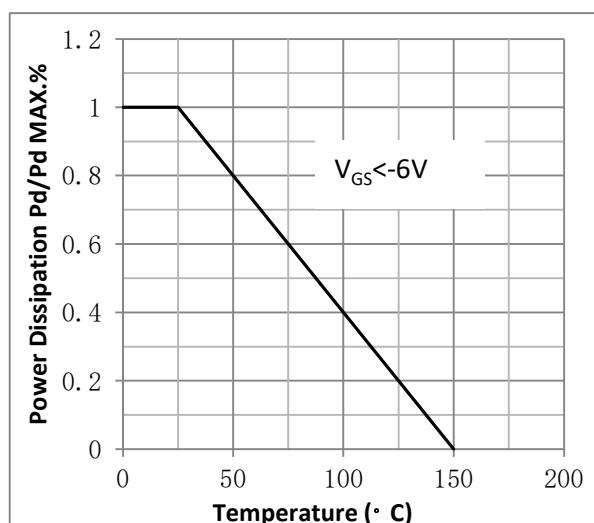


Fig.4 Typical output Characteristics

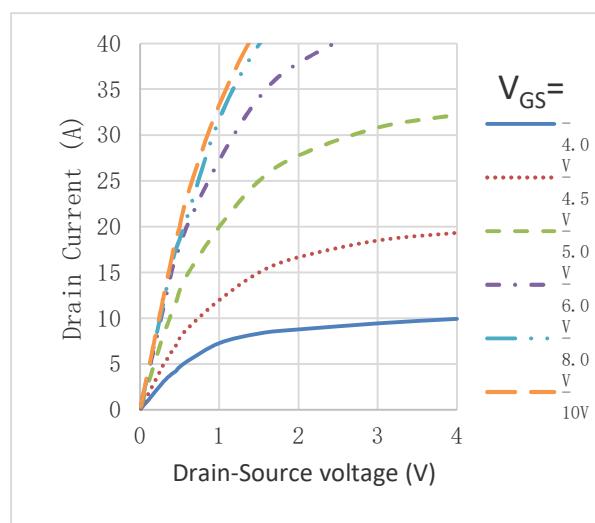


Fig.5 Threshold Voltage V.S Junction Temperature

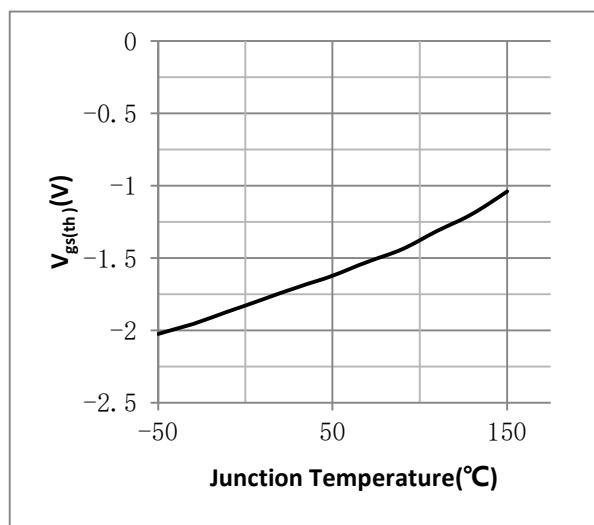


Fig.6 Resistance V.S Drain Current

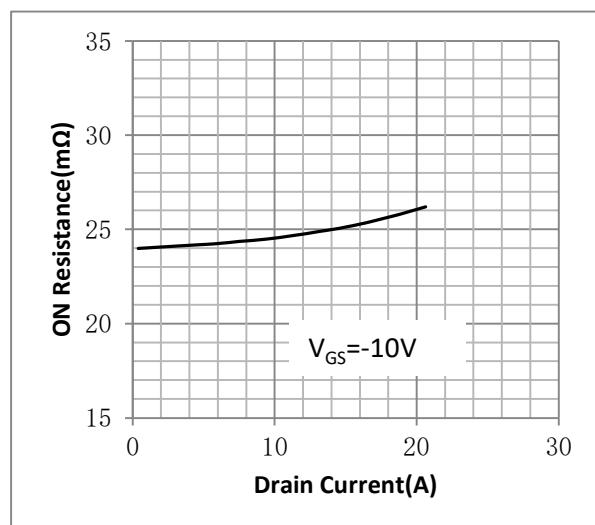


Fig.7 On-Resistance VS Gate Source Voltage

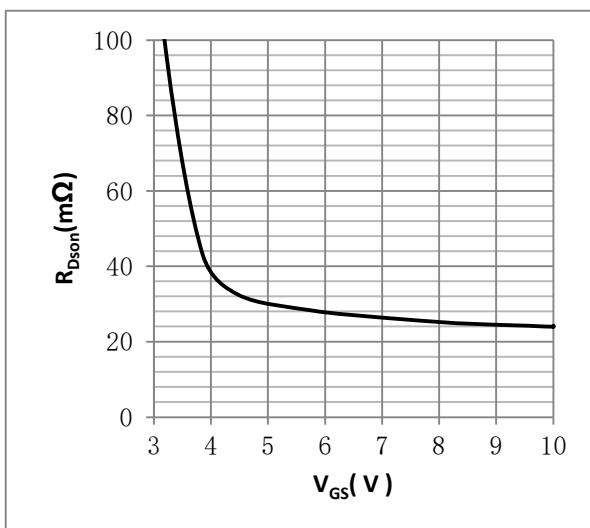


Figure 9. Diode Forward Voltage vs. Current

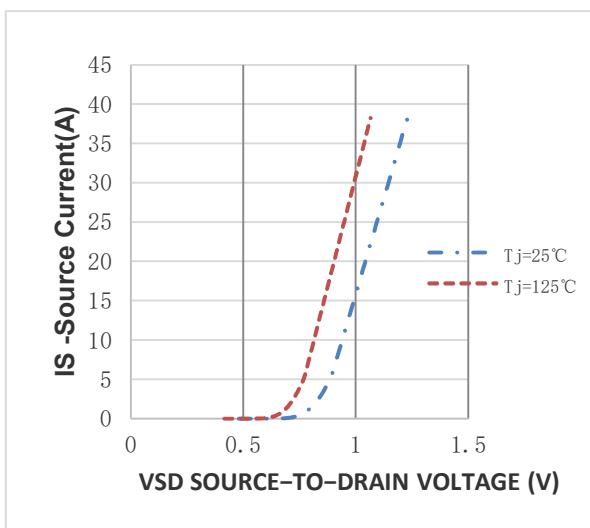


Fig.11 Safe Operating Area

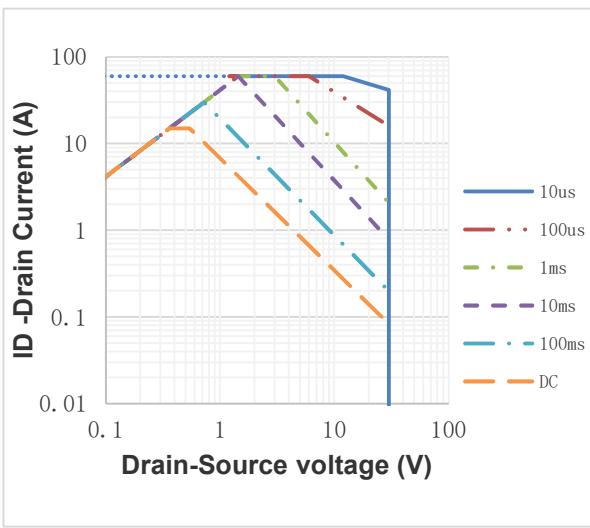


Fig.8 On-Resistance V.S Junction Temperature

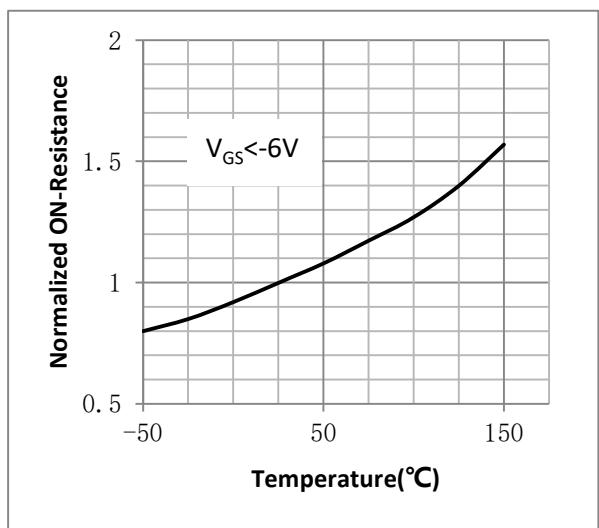
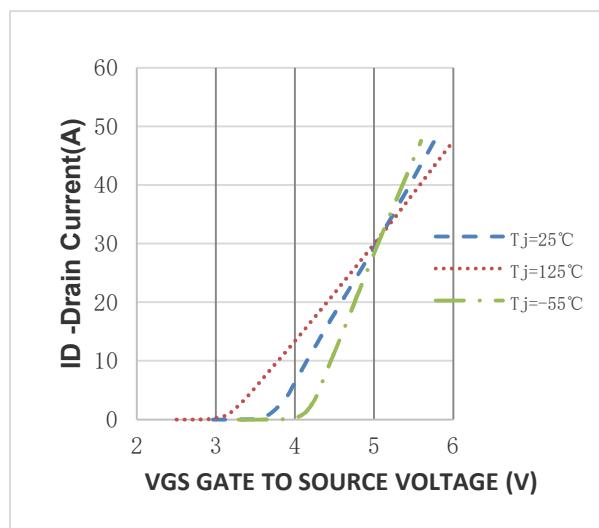
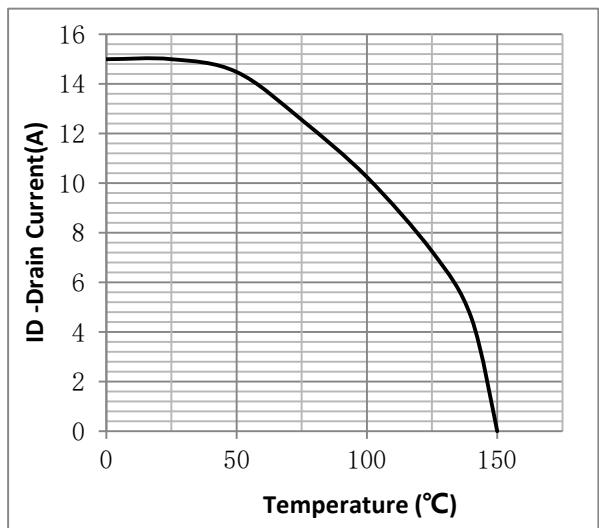
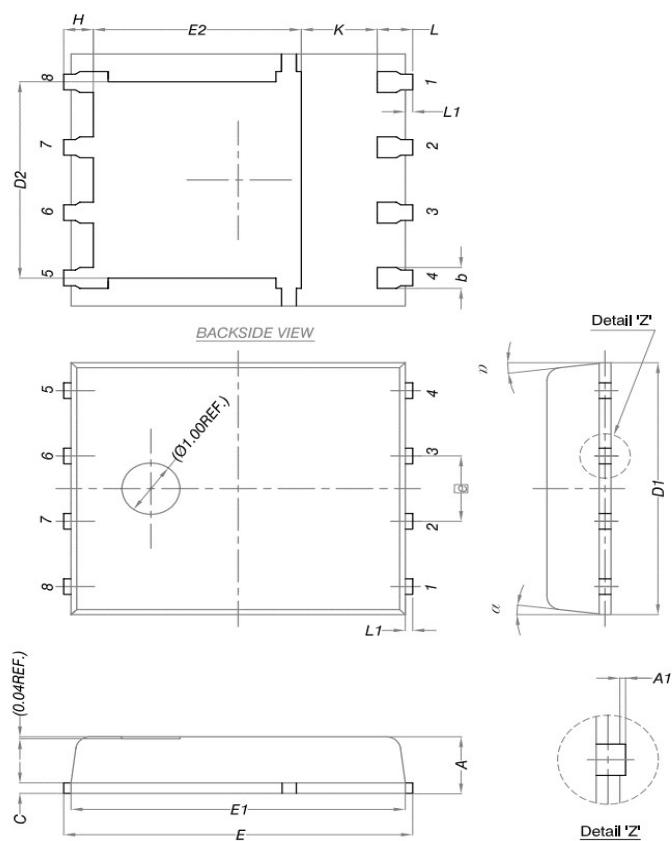


Figure 10. Transfer Characteristics

Fig.12 ID vs. Case Temperature⁽²⁾



•DFN3*3 Package Outline



DIM.	MILLIMETERS		
	MIN.	NOM.	MAX.
A	0.90	1.00	1.10
A1	0	-	0.05
b	0.33	0.41	0.51
C	0.20	0.25	0.30
D1	4.80	4.90	5.00
D2	3.61	3.81	3.96
E	5.90	6.00	6.10
E1	5.70	5.75	5.80
E2	3.38	3.58	3.78
e	1.27 BSC		
H	0.41	0.51	0.61
K	1.10	-	-
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
α	0°	-	12°

**Note:**

① Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate;

② Practically the current will be limited by PCB, thermal design and operating temperature. VGS=-10V.

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Revision History

Version	Date	Change
A	2020.3.10	NEW
B	2022.10.30	Add ESD level
C	2023.12.28	1.Add dynamic characteristics 2.Fig1~12 modify
D	2024.5.14	Correct Cxss and Qg value